

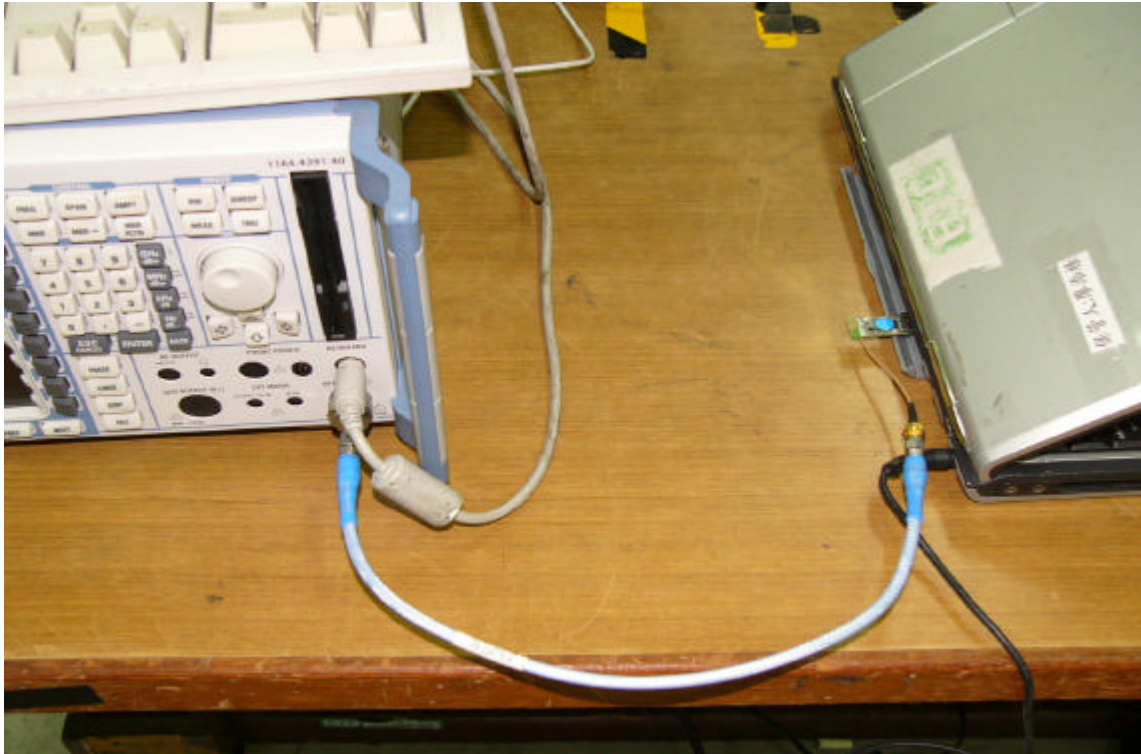
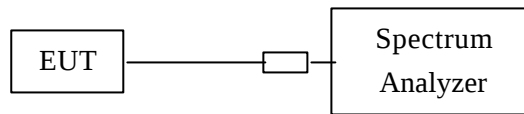
Photos of Radiation Measuring Setup



Photos of Conduction Measuring Setup



Figure 4 : Measurement configuration.



7.3 Measurement Equipment

Equipment	Manufacturer	Model No.	Next Cal. Due
Spectrum Analyzer	Rohde & Schwarz	FSP	06/30/2006
Attenuator	Weinschel Engineering	1	N/A

7.4 Measurement Data

Test Date : Jun. 07, 2005 Temperature : 23 °C Humidity : 55 %

- a) Channel Low : Adjacent Hopping Channel Separation is 1000 kHz
- b) Channel Middle : Adjacent Hopping Channel Separation is 1000 kHz
- c) Channel High : Adjacent Hopping Channel Separation is 1000 kHz

Note : 1. Please see appendix 2 for Plotted Data

2. The expanded uncertainty of the hopping channel separation tests is 2dB.